### SMDCM5040 Series Common Mode Line Filter







### ◆特征:

- 适用大电流的片式共模滤波器
- 所有系列产品的形状均控制在最小限度 同时共模阻抗超过了300~1000(10MHz时) 可大幅强制共模噪音
- 产品的高度尺寸也被控制在较低水平 能够适应不断小型轻量化的便携 式设备的高密度化趋势
- 符合 RoHS,无卤和 REACH

### ◆用途:

- 用于应对电子设备的电源线噪音 (笔记本电,包服器,电池,等)
- 适合车载大电流电路
- 无线充电电源装置

#### ◆环境:

工作温度: -55℃ 至+125℃(包括线圈自身温升)

### ◆试验设备:

- 电流:HP4284+42841A 或词等仪器
- 阻抗:E4991+ HP16092 测试夹具或同等仪器
- 直流电阻: Chroma 16502 或同等仪器

### ◆产品型号:

	•			
1	-×			
	类型 Type			
SMDCM	贴片共模滤波器 SMD Common Mode Line Filter			
4				

包装 Packing		
B	散装Bulk Package	
T	编带Tape & Reel	

#### Features:

- Chip common mode filter for large current applications
- The shape of all series products is controlled to a minimum and the common mode inpedance exceeds 300~1000 (at 10MHz), which can greatly suppress common mode noise
- Compatible with high-density portable devices, which are always being roade smaller and lighter, because the height has been reduced
- RoHS, Halogen Free and REACH Compliance

### **Applications:**

- Power line noise countermeasure for electronic
   equipment (Notebook, server applications, Battery, etc.)
- Best for high current circuit such as car
- wireless charging and power device design

#### **Environmental Data:**

Operating Temperature: -55°C to +125°C
 (Including coils self-temperature rise)

#### Test Equipment:

- Isat & Irms: HP4284+42841A or equivalent
- Impedance: E4991 analyzer with HP16092 test fixture or equivalen
- DCR:Chroma 16502 or equivalent

#### **Product Identification:**

_	2	_ <del>``</del>		
	外形尺寸(L×W×hi) (mm)			
	External Dimensions (L×W×H)			
	(mm)			
	5040	4.8×5.0×4.5		

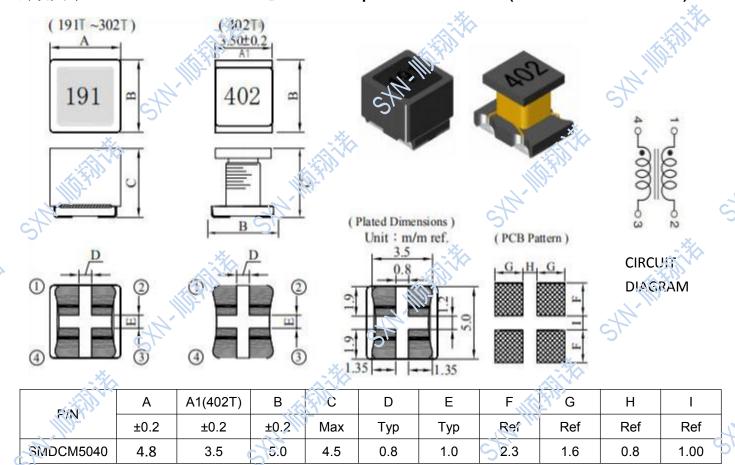
<u>102</u>

③ Impedance 1000 Ω



# ◆外观尺寸:

# Shape and Dimensions (dimensions are in mm)



## ◆规格特性:

# Specifications:

SMDCM5040 Series Electrical Characteristics (Electrical specifications at 25℃)

Part Number	Comກວກ mode !mpedance (Ω) @100MHz Typ	Inductance (uH) @100KHz/0.1V Typ	DC Resistance (Ω) Max	Rated Current (A) Max	Rated Voltage (V) Max	Insulatio Resistance (MΩ) Min	Marking
SMDCM5040-191T	190	0.6	0.02	5.0	50	10M	191
SMDCM5040-351T	350		0.04	2.0	50	10M	351
SMDCM5040-501T	500	2.3	0.05	1.8	50	10M	501
SMDCM5040-102T	1000	2.7	0.06	<b>.</b> 1.5	50	10M	162
SMDCM5040-152T	1500	3.6	0.10	1.0	50	10M	152
SMDCM5040-302T	3500	6.0	0.20	0.5	50	10M	302
SMDCM5040-402T	4000	8.0	0.30	0.2	50	10Ni	402

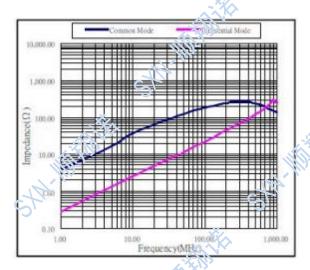
• Rated Current: the actual value of DC current when the temperature rise isΔT 40 °C (Ta=25 °C).

# Common Mode Choke

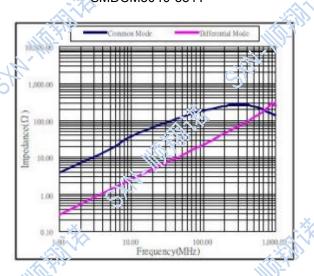


# • Typical Impedance versus Frequency

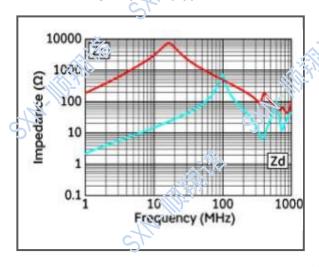
SMDCM5040-191T



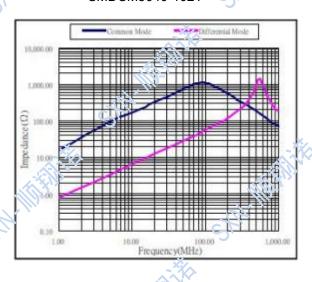
SMDCM5040-351T



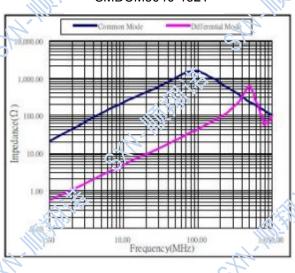
### SMDCM5040-501T



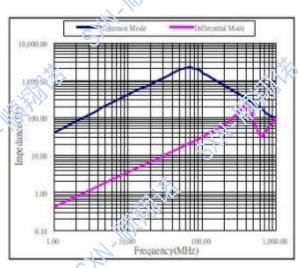
SMDCM5040-102T



SMDCM5040-152T

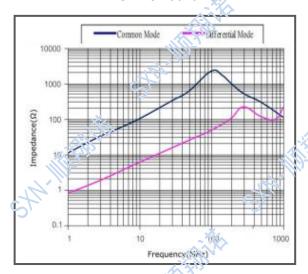


SMDCM5040-302T





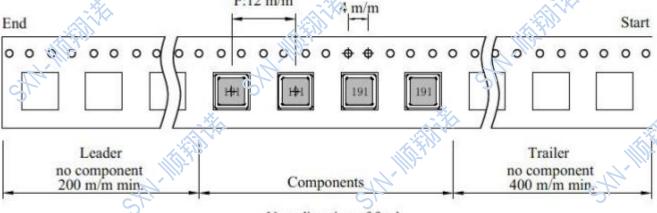
SMDCM5040-402T



# ◆产品包装:

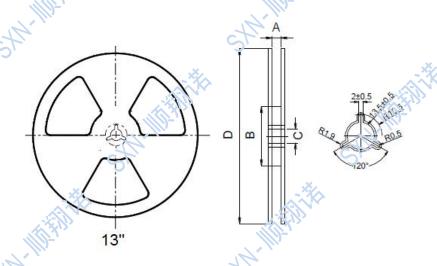
# Packaging:

• Tape and Reel Specifications: (Dimensions are in mm)
P:12 m/m



User direction of feed

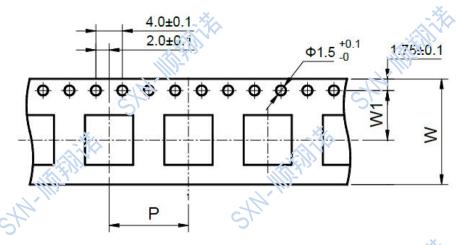
## • Reel Dimensions (mm)





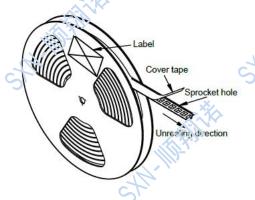
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## ●Tape Dimension (mm)

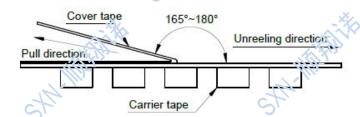


Part No.	Tape Dimension		Reel Dimensions			REEL	Inside	Outside	
Part No.	W	P	W1	Α	В	C D	(PCS)	Box(PCS)	Carton(PCS)
SMDCM5040	16.0	12.0	7.5	16.5	100	13 330	1000	3000	12,000
Cover tone no	- Cal					SI		9	)

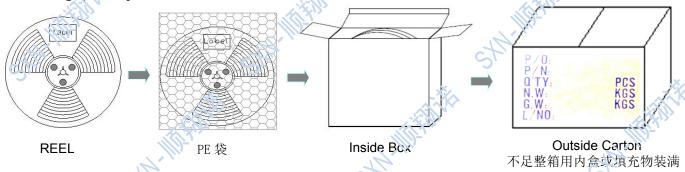
## • Cover tape peel of condition



- a) Cover tape peel force shall be 10 to 120g
- b) Noodle strip peeling angle165° to 180°



# Packing quantity





# ◆可靠性测试:

# Reliability Testing:

<u> </u>		Teliability resting:
Items	Requirements	Test Methods and Remarks
	1. Pulling fest:	Solder the inductor to the testing jig using leadfree
	Define: A: sectional area of terminal	solder. Then apply a force in the
Terminal Strength	A≦8mm2 force≥5N time:30sec	Keep time: 10±1s Speed: 1.0mm/s
Reference docu	Enm2 <a 10n="" 10sec<="" 20mm2="" force="" td="" time:="" ≤="" ≥=""><td></td></a>	
ments: GB/T	20mm2 <a 1053c<="" force="" td="" time:="" ≥20n=""><td>1100</td></a>	1100
2423.60-2008	2.Solder paste thickness:0.12mm	
端子強度(SMT)	3.Meet the above requirements without any	
	loose terminal	The state of the s
5/19	4 Tampinal diamatatida nana 0.25 cd	<u> </u>
	1.Terminal diameter(d) mm 0.35 <d≤< td=""><td>Pull Force:the force shall be applied gradually to</td></d≤<>	Pull Force:the force shall be applied gradually to
		the tem inal and thenmaintained for 10 seconds.
erminal Strength	10sec2.7erminal diameter(d) mm0.50 < d <	
Reference docu	0.80 Applied force:10N Duration:	
ments: GB/T	10sec3.Terminal diameter(d) mm0.80 < d	C.S.
2423.60-2008	1.25Applied force:20N Duration:	Pulling test
端子強度(DIP)	10sec4.Terminal diameter(d) mmD>	
	1.25Applied force:40N Duration:	
	10sec5.Meet the above requirements	<i>1111</i> 2.
	without any loose terminal.	47,
St	1.No visible mechanical damage.	1.Solder the inductor to the test jig (glass epoxy
	*/_	board
		2 shown in Using a leadfree solder. Then apply a
		force in the direction shown
Resistance to Flexure	Tills	3.Flexure: 2mm.
JIS C 5321:1997	et st	4.Pressurizing Speed: 0.5mm/sec.
抗弯曲性试验	.x.	5.Keep time: 30 sec.
X		4.20
		R230
The state of the s	EX.	45[1.772] + 45[1.772] + Flexure
SI	3,	49[1372] 49[1772] 49 1
	1.No case deformation or change	A 100
Dropping	inappearance.	1.Drop the packaged products from 1m high in 1
Reference documents:		angle, 3 ridges and 6surfaces, twice in each
GB/T 2423.7-2018	2.No short and no open.	direction.
落下試驗	2)	3
x82.	-%	4 Caldan tama atus (MA 10°C
Solderability	1.No visible mechanical damage.	1.Solder temperture:240 ±2 °C
Reference documents:	2. Wetting shall exceed 1.370 coverage for	2.Duration: 3 sec.
GB/T 2423.28-2005	3.Terminals must have 95% minimum solder	3. Solder: Sn/3 0Ag/0.5Cu.
可焊性试验	coverage	4.Flux: 25% Resin and 75% ethanol in weight
-1		38∕.
<u> </u>	L 10/2	<u></u>



Items	Requirements	Test Methods and Remarks
	1.No visible mechanical damage.	1. Sorder the inductor to the testing jig (glass epoxy
	2. Inductance change: Within ±10%.	boardshown in ) using leadfree solder.
	3.2 factor change: Within ±20%.	2.The inductor shall be subjected to a simple
	Cu pad Solder mask	harmonic motion having total amplitude of 1.5mm,
		the frequency being varieduniformly between the
		approximate limits of 10 and 55 Hz.
Vibration		3.The frequency range from 10 to 55 Hz and
Reference documents:		return to 10 Hz shallbe traversed in approximately
GB/T 2423.10-2019	Glass Epoxy Board	1 minute. This motion shall be applied for a period
振動試验		of 2 hours in each 3mutually perpendicular
	William Commencer	directions(total of 6 hours).
	14. M.	Freq
C	DF. 21	55Hz \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
X <sub>V</sub>	-%	
		10Hz V V V V Time
eth, w	1.No visible mechanical damage.	1.Start at (125 ℃) for T time, rush to (-40 ℃) for T
2,	2. Inductance change: Within ±10%.(Mn-Zn:	_X/
		2.Traneforming interval: Max. 20 sec.
Thermal Shock	3.Q factor change: Within ±20%.	3.Tested cycle: 20 cycles.
Reference documents:		4.The chip shall be stabilized at normal condition
GB/T 2423.22-2012	ST'	for 1~2 hours
Method Na	<b>.</b> <b>.</b>	30 min. 30 min.
冷热冲击试验		Ambient
		Temperature 30 min.
	1 / Mr.	20sec. (max.)
Sta	ST	51
	1.No visible mechanical damage.	1.Temperature:M(-40±2°C)
	2. Inductance change: Within ±10%.(Mn-Zn:	2.Duration: 96±2 hours
Low temperature Storage	Within ≦30% )	3.The chip shall be stabilized at normal condition for
Reference documents:	Q factor change: Within ±20%.	1~2 hoursbefore measuring.
GB/T 2423.1-2008	9,	Room
Method Ab		Temp 96H Test
低温储存试验		97H 98H Time
Marie	illin.	M°C temperature
th.	cth	Temp
つ'	<i>y</i>	, to

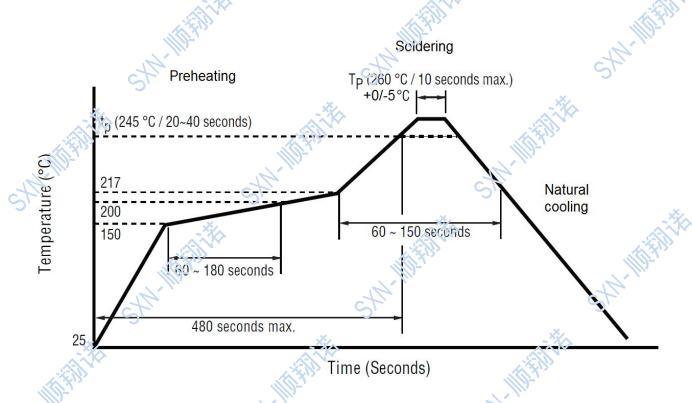


Items	Requirements	Test Methods and Remarks
	1.No visicis mechanical damage.	1. Temperature: N(125 $\pm$ 2 $^{\circ}$ C).
High temperature	2. Inductance change: Within ±10%.(Mn-Zn:	2.Duration: 96±2 hours
	Within ≤30%)	3.The chip shall be stabilized at normal condition
o .	3.Q factor change: Within ±20%.	for 1~2 hoursbefore measuring.
GB/T 2423.2-2008	~~ <b>*</b>	Temp High temperature
Method Bb		N°C
高温储存试验		Room
同価値行风巡	St	Temp
	1.No visible mechanical damage.	1.Temp⊝rature: 60±2℃
	2. Inductance change: Within ±10%.(Mn-Zn:	2.Hamidity: 90% to 95% RH.
Damp Heat	Within ≦ 30% )	ই.Duration: 96±2 hours.
(Steady States)	3.Q factor change: Within ±20%.	4.The chip shall be stabilized at normal condition
Reference documents:	St.	for 1~2 hoursbefore measuring.
GB/T 2423.3-2016	3 <del>2</del> /2	Temp & Humidity
恒定湿热试验		93%RH High temperature High humidity
		Room Conditions
	14,111	0 Test 0 96H 97H 98H Time
Heat endurance of	1.No significant defects in appearance.	51
Reflow soldering	2. △ L/L ≤ 10% (Mn-Zn: △ L/L ≤ 30%)	1.Refer to the above reflow curve and go through the reflow for twice.
Reference documents:	3. ∆ Q/Q ≨ 30% (SMD series only)	2.The peak temperature : 260+0/-5℃
GJB 360B-2009	4. A DOR/DCR ≤ 10%	Proposition Polaticis : 200 to to the same of the same
回流焊耐热性试验	7.1118	the state of the s
C	No case deformation or change in	To dip parts into IPA solvent for 5±0.5Min,then
Resistance to solvent	appearance or obliteration of marking	drying them at room temp for 5Min,at last ,to
test		brushing making 10 times.
Reference documents:		<u> </u>
IEC 68-2-45:1993		A. In
耐溶剂性试验	eth	ST
2,	3	×.
Overload test	1.During tree test no smoke, no peculiar,	
Reference documents:	smell, no fire	(24),
JIS C5311-6.13	2.7% characteristic is normal after test	Apply twice as rated current for 5 minutes.
过负荷试验	Str	St
voltage resistance test	1.During the test no breakdows	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\
- 1	2.The characteristic is normal after test	d Fan wards with A State of the
MIL-STD-202G Method		1. For parts with two coils
301	747	2. DC1000V, Current: 1mA, Time: 1Min.
绝缘耐压测试	ST	Refer to catalogue of specific products
	.x.	×.



◆推荐回流焊温度曲线

## Recommended reflew soldering curve:



The recommended reflow conditions as above graph, is set according to our soldering equipment. DUE to various manufactures may have different reflow soldering equipment, products, process conditions, set methods. And so on, when setting the reflow conditions, Please adjust and confirm according to users' environment/equipment.



### 使用注意事项

### REMINDERS FOR USING THESE PRODUCTS



● 保存时间为12 个月以内,保存条件(温度5~40°C以下、湿度35 ~ 66%RH 以下),需充分注意。若超过保存时间,端子电极的可焊性将可能老化。

The storage period is within 12 months. Be sure to follow the storage conditions (temperature: 5~40°C, humidity: 35 to 65% RH or less). If the storage period elapses, the soldering of the terminal electrodes may deteriorate.

- 请勿在气体离蚀环境(盐、酸、碱等)下使用和保存。
  - Do not use or store in locations where there are conditions such as gas corrosion (salt, acid, alkali, etc.).
- 手上的油脂会导致可焊性降低,应避免用于直接接触端子。

  Don't touch electrodes directly with bare nands as oil secretions may inhibit soldering Alv
  - Don't touch electrodes directly with bare hands as oil secretions may inhibit soldering Always ensure optimum conditions for soldering
- 请小心轻拿轻放,避免由于产品的跌落或取出不当而导致的损坏。
  - Please always handle products carefully to prevent any damage caused bydropping down or inappropriate removing.
- 端子过度弯曲会导致断线,请不要过度弯曲端子。
  - Don't bend the terminals with excessive stress in case of any wire fracture.
- 不要清洗产品, 如需要清洗时请联系我司。
  - Don't mase coils by yourself and please contact SXN if necessary.
- 请勿将本产品靠近磁铁或带有磁力的物体
  - Don't expose the products to magnets or magnetic fields
- 在实施焊接前,请务必进行预热。预热温度与焊接温度及芯片温度的温度差要在150°C 以内。
   Before soldering, be sure to preheat components. The preheating remperature should be set so that the temperature difference between the solder temperature and chip temperature does not exceed 150°C.
- 安装后的焊接修正应在规格书规定的条件范围内。若加热过度可能导致短路、性能降低、寿命减少。
  Soldering corrections after mounting should be within the range of the conditions determined in the specifications. If overheated, a short circuit, performance deterioration, or lifespan shortening may occur.
- 装置会因通电而自我发热(温度上升),因此在热设计方面需留有充分余地。
  Self heating (temperature increase) occurs when the power is turned ON, so the tolerance should be sufficient for the set thermal design.
- 非磁屏蔽型在基板设计时需注意配置线圈,受到电磁干扰可能会导致误动作。
  Carefully lay out the coil for the circuit board design of the non-magnetic shield type. A malfunction may occur due to magnetic interrerence.